



Figure 1. (a) Photoemission spectra measured at a photon energy of 270 eV for 0.25% Br₂/MeOH etched, 10% HCl etched, 250°C vacuum annealed, UV ozone oxidation, and 280°C H₂S treated Cd_{0.9}Zn_{0.1}Te 111A surfaces, with intensities normalized to Cd 4d peak; (b) cross-sectional SEM image of 280°C H₂S treated Cd_{0.9}Zn_{0.1}Te 111A surface; (c) EDX mapping scan on the interface shown in (b); and (d) EDX line scans along the interface highlighted in (b).